

## ABSTRACT

There is described an improved Surface Reflectance Instrument which achieves more complete detection of surface defects in the nature of small particles. One of the  
5 improvements is the use of an elliptical integrated cavity with internal surface mirrors, and another the use of a position sensing diode as the detector for the scattered light. Other improvements and the use of a stable laser at a particular wavelength resulting in greater detection are also described.

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